TKESHELASHVILI, N.K., kand.tekhn.nauk; ASHCHIAN, O.A., kand.tekhn.nauk; OSTASHVILI, T.I.

Mechanical injuries to tea leaves and investigating their effect on the quality of production for the purpose of improving designs of plucking machinery. Trudy VNIICHP no.1:71-82 (MIRA 12:5)

(Tea machinery)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

NOGAYDELI, A.I.; TKESHELASHVILI, R.Sh.; NAKAIDZE, L.I.

Reaction of dimethyldichlorosilane with 1,4-dihydro-1, 4-dilithium-\(\beta\)-methylnaphthalene. Soob. AN Gruz. SSR 38 no. 3:559-566 Je '65. (MIRA 18:12)

1. Tbilisskiy gosudarstvennyy universitet. Submitted Jan. 30, 1965.

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

ACCESSION	NR: AP5022931	WW/RM
AUTHOR: 7	المراركة الم	UR/0062/65/000/008/1396/1402
TITLE: Re	action of dimethyl- and phe	vianov, K. A.; Nogaydeli, A. I.  nylmethyldichlorosilanes with 1,4-dilithium
-1,4-dihyd	ronaphthalene	my methylulchiorosilanes with 1,4-dilithium
SOURCE: A	N SSSR. Izvestiya. Seriya ki	himicheskaya, no. 8, 1965, 1396-1402
TOPIC TAGS	: dimethyldichlorosilane, d	condensation reaction
ABSTRACT: derivatives of oligomes	The reaction of dimethyl- as of naphthane was studied to	and phenylmethylchlorosilanes with dilithium to determine its usefulness in the synthesis
H I	yrchiorosilane proceeds acc	cording to the following scheme
<b>^</b> ×	CH <sub>0</sub> H CH <sub>0</sub> CH <sub>0</sub> H CH <sub>0</sub> Si 0	CHan H CHa 7 CHan W CH.
H L	сн. Сн.	CH. CH. CH. CH.
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#### L 1128-66

ACCESSION NR: AP5022931

The reaction product is a tetramer with a boiling temperature of 218-220°C (at 1 mm Hg). In the absence of moisture this reaction proceeds according to

This scheme was followed also in the case of condensation with phenylmethyldichlorosilane. In this case the products were: a dimer boiling at 200-205°C (1 mm Hg) and a tetramer boiling at 245-250°C (1 mm Hg). Boiling temperatures at reduced pressure, refractive indices, and molecular weights (elemental analysis) were determined for all reaction products. In order to confirm the structure, the reaction products were hydrolyzed to the corresponding dihydroxy-derivatives with various degrees of

Card 2/3

L 1128-66
ACCESSION NR: AP5022931

polymerization and transformed into other derivatives. Orig. art. has: 2 tables.
ASSOCIATION: Institut elementoorganicheskikh soyedineniy Akademii nauk SSSR
(Institute of Elemental Organic Compounds, Academy of Sciences, SSSR)
SUBMITTED: 09Jul64

ENCL: 00

SUB CODE: GC, OC

NO REF SOV: 001

OTHER: 000

NCGAIDELI, A.I.; TKESHELASHVILI, R.Sh.

Condensation of acetylene with acetone in the vapor phase in the presence of caustic soda deposited on activated gumbrin. Zhur. prikl. khim. 38 no.7:1639-1640 Jl '65. (MIRA 18:7)

1. Tbilisskiy gosudarstvennyy universitet.

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

TKESHELASHVILI, T.V.

Nematelegical medifications fellowing a major resection of the small intestine. Seeb. AN Gruz. SSR 17 no.4:343-350 56. (MIRA 9:9)

1. Akademiya nauk Gruzinskey SSR, Institut eksperimental ney i klinicheskey khirurgii i gematelegii, Tbilisi. Predstavlene akademikem K.D. Eristavi. (INTESTINES -- SURGERY) (BLOOD -- ANALYSIS AND CHEMISTRY)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

TRESHELASHVILI, T.V.

Punctional associations between segments of the small intestine.
Soob.AM Gruz.SSR 16 no.4:325-330 '55. (MLRA 8:12)

1. Akademiya nauk Gruzinskoy SSR, Institut eksperimental'noy i klinicheskoy khirurgii i gematologlim Tbilisi. Predstavleno deystvitel'nym chlenom Akademii K.D Eristavi.

(Intestines)

TKESHELASHVILI, T.V.

Nerve regulation of the motor function of the small intestine. Soob.AN Gruz.SSR 17 no.2:163-168 '56. (MLRA 9:8)

1. Akademiya nauk Gruzinskoy SSR, Institut eksperimental'noy i klinicheskoy khirurgii i gematologii, Tbilisi. Predstavleno deystvitel'nym chlenom Akademii K.D. Eristaii.

(INTESTINES)

1KHSAHAASAVIA, T.V.

USSR/Human and Animal Morphology - Blood. General Problems.

R-4

Abs Jour

: Referat Zhur - Biologii, No 16, 1957, 70558

Author

Tkeshelashvili, T.V.

Title

: Changes in the Blood After Extensive Resection of the

Small Intestine

Orig Pub

: Soobshch. AN GruzSSR, 1956, 17, No 4, 343-350

Abstract

: In dogs after resection of 35-60% of the total length of the small intestine the blood picture changed relatively little. The qu. of chlorides and N was in the limits of lower and higher normals.

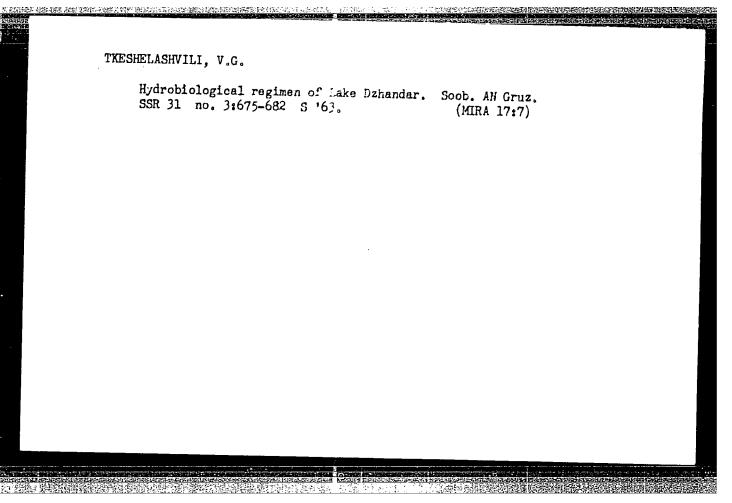
Card 1/1

- 102 -

TKESHELASHVILI, T.V.; KEVLISHVILI, G.Ye.; ABESADZE, A.I.

Significance of plasma substitute made from gelatin in the complex therapy of acute radiation sickness. Soob. AN GruzSSR 37 no.2:475-479 F '65.

(MIRA 18:3)



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inHamedary, N. A.

21903. Therefore, N. A.
Cherkeeskiy sort yaddoni aguremiy. Trucy Krasnodersk. in-ta picken. prom-sti, vpp. 7, 1949,c. 37-42. - Bibliogr: 8 nazv.

S0: letopis' Zhurnal'nykh Stateyy, No. 29, Moskva, 1949.
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Thiractorial, N. A.

21902. TKHACTORIAN, N. A.

Pomoloricleskaya i khoayamstvennaya kharakteristika cherkesskogo sorta slivy Khatsepke. Trudy krasnodarsk. in-ta misheh. promesti, Vyr. 7, 1949, s.

S0: Letopis' Zhurnal'nykh Statey, No. 29, Moskva, 1949.

333h3. Osnovnyye Cherkesskiye Sorta drushi. Sad I Ogorod, 19h9, No. 10, C. 25-30

So: Leto is' Ehrmal'nykh Statey Vol. h5, Moskva, 19h9

TYHACUSHEV, Mukha Akhmedovich

(Kuban' Agriculturel Inst) - Academic during of Doctor of Agricultural Sciences, based on his defense, 4 May 1955, in the Council of the All-Union Sci Res Inst of Flant Cultivation, of his dissertation entitled: "Adygey (Cherkassian) Gardens."

Academic degree and/or title: Doctor of Sciences

SO: Decisions of VAK, List no. 27, 24 Dec 55, Byulletin' NWO STSP Uncl. JFRO/NY 547

TKHAGUSHEV, N. A.

"Adygog (Circassian) Orchards." All-Union Order of
Lenin Academy of Agriculture imeni V. I. Lenin, All-Union Inst of
Plant Breeding, Krasnodar, 1955. (Dissertation for the Degree of
Doctor in Agricultural Sciences)

SO: M-955, 16 Feb 56

7.	TKHAGUSHEV.	1.	
1.	TVUURODUUA	!i -	А.

- 2, USSR (600)
- 4. Nuts
- 7. Widespread introduction of nut growing. Sad i og. ne.10, 1952

9. Monthly List of Russian Accessions, Library of Congress, January 1953, Unclassified.

TKHAKAKOV, U.U.

"The Protein Need of Highly-productive Cows";

dispertation for the degree of Candidate of Agricultural Sciences (awarded by the Timinyazav Agricultural Academy, 1962)

(Investiva Timinyazavskoy Sel'akokhozyaystvennoy Akademii, Moscow, No. 2, 1963, pp 232-236)

POPOV, I.S., akademik; SKOROBAGATYKH, N.N., kand. sel'skokhoz. nauk; TKHAKAKHOV, Kh.Kh., kand. sel'skokhoz. nauk; DAVYDOVA, L.P., kand. sel'skokhoz. nauk; FESYUN, G.I., aspirant

Protein requirements of high-yielding cows. Izv. TSKHA no.6: 191-202 '63. (MIRA 17:8)

1. Vsesoyuznaya akademiya seliskokhozyaystvennykh nauk imeni Lenina (for Popov).

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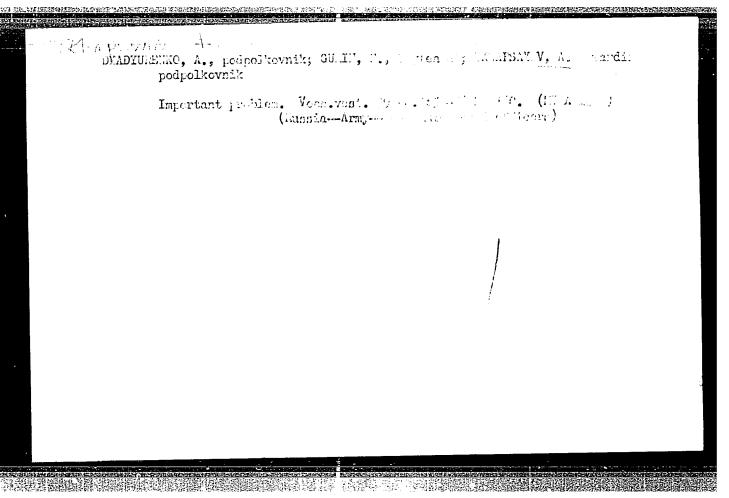
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The type FTA-M facsimile transmitter. Vest.sviazi 17 no.2:3-5
F '57.

1. Starshiy inzhener Tekhnicheskogo upravleniya Ministerstva
syyazi SSSR (for Bogorodskiy) 2. Nachal'nik laboratorii Nauchnoissledovatel'skogo instituta Ministerstva radiotekhnicheskoy
promyshlennosti (for Tikhanov).

((Phototelegraphy)



KUSTKHOV, Anatoliy Khzubbiyevich; TKHAGHAKIT, A.I., 1900.

[Outline of the history of briance broudy of the Kabardino-Balkar, J.J.H.] Select 1: the reference okogo izuchenida Kabardino-Balkarii, Indianik, Salar di Balkarskoe knizhnoe izh-vo, 1962. [Jun 1980]

SHAUTSUKOVA, L.K., starshiy prepodavatel; TKHASHOKOV, N.I., student; KHAPAZHEV, T.Sh., student; KHAKULOV, L.A., student; DZOBLAYEV, A.A, student.

Physiological and biochemical change during amytal-induced sleep in rabbits. Uch.zap.Kab.gos.ped.inst. no.10:113-127 '56. (MLRA 10:3)

(SEEP-THEREPEUTIC USE) (AMATYL))

THASHONON, N.I.

USSR/Pharmacology, Toxicology - Narcotics.

U-1

: Ref Zhur - Biol., No 3, 1958, 12845 Abs Jour

Shautsukova, L.K., Tkhashonov, N.I., Khapazhev, T.Sl., Author

Khakulov, L.A., Dzoblayev, A.A.

Inst

: Certain Physiologic and Biochemical Changes in Rabbits Title

During Amytal-Induced Sleep.

Uch. Zap. Kabardinsk. gos. ped. in-t, 1956, vyp. 10, 113-Orig Pub

126.

長**海洋別都進行表記在於非經濟語等等等**第2章。12章 12章 12章

Experiments were performed on male rabbits. A 15% solu-Abstract

tion of sodium amytal in a dose of 1.5-2 ml. was administered into the ear vein on 3 successive days. During the amytal-induced sleep, total plasma proteins decreased in proportion to the duration of the sleep. Blood sugar and iron decreased during the first two days but then began to increase until the sleep was terminated. During the amytal-induced sleep there was a decrease in Hb. and

Card 1/2

CIA-RDP86-00513R001755930004-7" **APPROVED FOR RELEASE: 07/16/2001** 

USSR/Pharmacology, Toxicology - Narcotics.

U-1

Abs Jour : Ref Zhur - Biol., No 3, 1958, 12845

in the number of REC, a slight leucocytosis and a shift of the differential white count to the leucopenic side but with an increase in all these indices when the sleep ended. The changes in Hb. paralleled those in blood iron. The authors surmise that the efficacy of the protective inhibition of sleep may be judged by the biochemical and physiologic changes.

Card 2/2

(1) 1945. "OUR EXPLORATION SOT/213 X Internstituted Conference on the Princetal line of Atomic Energy. 2nd, The Princetal lines of Atomic Energy.	ELID	FIGURES: This book is intended for scientists, angineers, prycitiess, and N biologists angaged in the production and application of scientific nearest to biologists and the passential teachers are not an application of scientific scientific of higher technical schools where maches science and tempor; and for the general public interested in stone science and tempolars and for the countries are notine 6 of a Grounes set of reports delivered by Soriet originates at the Second Interestional Conference on the Personal Uses of Atomic Energy hold in Genera from September 1 to 13, 1993. Wollies of contact and in a second science of the set of teocopes and their labeled compounds, 2) research results obtained settly the aid of teocopes in the field of chemistry, settlinery, and in the settle and originally and settline settles.		of the Anisal (Report No. 2314)  of the Anisal (Report No. 2314)  s		
') International Confe	Doklady sovetakibh Bosta Goriet Edsen Atomitader, 1999 Printed Eds. (fitle page): Lug (fitle page): freth. Eds. (1.0)	PURPOSS: This book passed belonging and passed belonging the passed by t	reason, Control of Pression Control of Pressio	of the Anisa M. Arfor, U.A., S.E. Peakina S.E. Echebic S.I. Echebic S.E. Echebic S.E. Echebic S.E. Echebic S.E. Echebic (Report Bo.,	<del></del>	
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ARIFOV, U. A., BARNOV, V. A., GUMANSKIY, G. A., KLEYN, G. A., PASHINSKIY, S. Z., TKHELIDZE, L. M., TSETSKHLADZE, T. V., CHKHETDUE, T. H., and SHENKOV, S. N.

"Treatment of Silkworm Cocoons by Radiation."

paper to be presented at 2nd UN Intl'. Conf. on the peaceful uses of Atomic Energy, Geneva, 1 - 13 Sept 58.

GADAKHABADZE, V.I.; TKHELIDZE, L.M.

The introduction of white cocoon and hybrid cocoons. Tekst.
prom. 16 no.8:8 Ag '56.

(Georgia--Silk manufacture)

TKHILADZE, G.

Methods for economizing drying oil.Stroitel' 2 no.6:8-9 Je '56.

(MERA 10:1)

1.Nachal'nik TSentral'noy nauchno-issledovatel'skoy laboratorii

Glavmosstroya.

(Painting, Industrial) (Emulsions)

SIZOV, Vasiliy Nikolayevich, prof., doktor tekhn.nau.?

RUDENKO-MORGUN, Ivan Yakovlevich, dots., kand. tekhn.
nauk; TKHILADZE, Georgiy Redionovich, inzh.; USENKO,
Vasiliy Mitrofanovich, kand. tekhn. nauk; SHVIDENKO,
V.N., prof., retsenzent; DANILEVSKIY, A.S., inzh.,
retsenzent; KUPERSHMIDT, L., red.

[Technology of construction] Tekhnologiia stroitel'nogo proizvodstva. [By V.I.Sizov i dr. Moskva, Vysshaia shkola, 1964. 613 p. (MIRA 1981)

TKHILADZE, G. R.; VOLCDARSKIY, G. I.

Drilling and Boring

A drill with hard-alloy tip for drilling holes in brick walls. Biul. strei. tekh. 9 no. 1. 1952. Minmashstroy, Trest Otdelstroy; Inzh.

SO: Monthly List of Russian Accessions, Library of Congress, April 1953, Uncl.

TKHILADZE, G.R., VOLODARSKIY, G.I.

Hose Couplings

Standard hose souplings. Biul.stroi.tekh., 9, no. 14, 1952.

9. Monthly List of Russian Accessions, Library of Congress, MOVEMBER 1952

- 1. TKHILADZE, G. R. ENG.
- 2. USSR (600)
- 4. Plastering
- 7. Rationalization of decorative work. Biul. stroi. tekh. 9 no. 19, 1952.

9. Monthly List of Russian Accessions, Library of Congress, January 1953, Unclassified.

- 1. TKHILADZE, G. R.
- 2. USSR (600)
- 4. Building Machinery; Plastering
- 7. Mobile plastering machine units Stroi. prom. 30, no. 4, April 1952 Nachal'nik Tsentral 'noy Nauchno-Issledovatel 'skoy Stantisii Tresta, Otdelstroy Minmashstroya.
- 9. Monthly List of Russian Accessions, Library of Congress, June 1952. UNCLASSIFIED

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

SHEPELEV, a.M., inzhener; TKHILADZE, G.R., inzhener nauchnyy redaktor.

[Paper hanging] Oboinye raboty. Moskva, Gos. izd-vo lit-ry po stroitel'stvu i arkhitekture, 1953. 31 p. (MLRA 7:7)

(Paper hanging) (Wallpaper)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

TKHILADZE, G.R., inzhener, nachalnik.

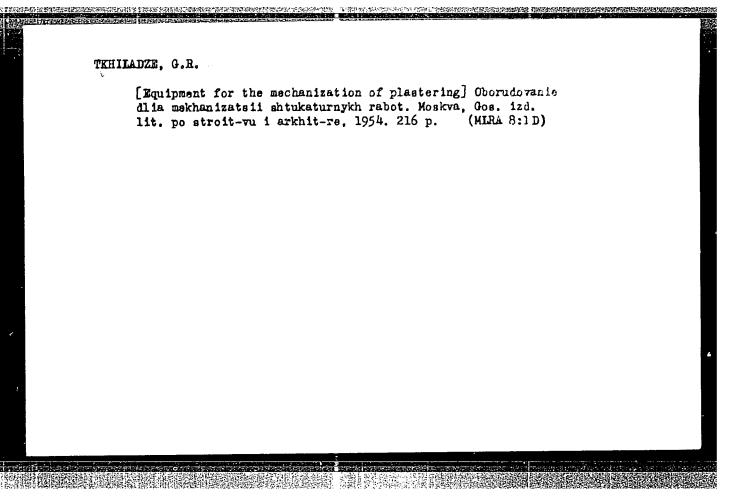
Finishing of building facades in winter. Stroi.prom. vol. 31 no.9:17-19 S '53.

1. Tšentral'naya nauchno-issledovatel'skaya laboratoriya Ministerstva stroitel'stva.

(Plastering--Cold weather conditions)

3352 TKHILADZE G. R. AND VOLODARSKIY, G. I.

Mekhanizatsiya parkegnykh rabot. M., 1954 16 S. S chert. 26 sm (Akad. Nauk SSSR. In-T Tekhn. Ekon informatsii. Periodich informatsiya tema no 17)
1.000 ekz B ts Na obl out Ne ukazany (54-57189) 694.631 a 3.0025



KRESTOV, M.A., redaktor; TKHILADEE, G.R., inzhener, nauchnyy redaktor;
BEGAK, B.A., redaktor; PEESON, M.N., tekhnicheskiy redaktor.

[Technology of finishing work] Otdelochnaia tekhnika. Pod obshchei red. M.A.Brestova. Moskva, Gos. izd-vo lit-ry po stroitel'stvu i arkhitekture. No. 2. 1954. 82 p. (MLRA 7:11)

1. Akademiya arkhitektury SSSR, Moscow. Laboratoriya otdelochnykh rabot.

(Façades) (Painting, Industrial)

TKHILADZE, G.R., inzhener.

For progressive technology in painting. Gor.khoz. Mosk. 29 no.11:
27-31 N '55.

(Painting, Industrial)

(Painting, Industrial)

MESHKOVSKAYA, V.V.; SMIRNOV, V.Ya.; ANTIPOV, M.M.; TKHILADZE, G.R.

Mebile mechanized machine for preparing paint components. Hats. i izobr.
predl.v strei.ne.123:6-9 155. (MIRA 9:7)

(Paint machinery)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

SMIRNOV, V.Ya.; PEREPELKINA, M.S.; ANTOROV, M.M.; TKHILADZE, G.R.

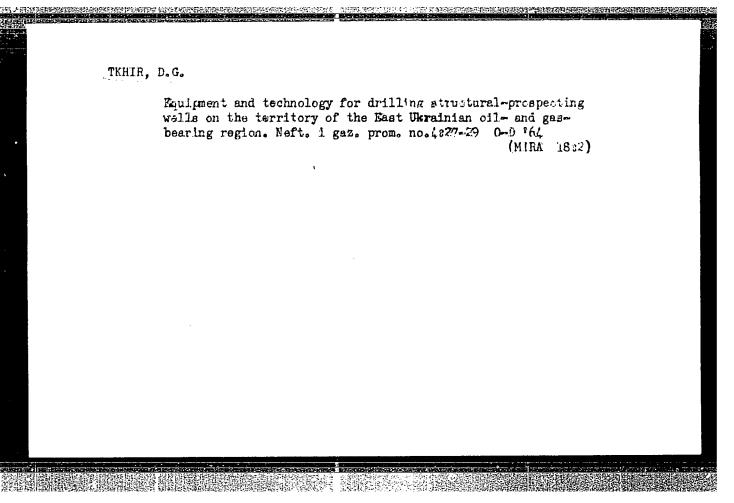
Mebile all-purpess machine for parquet fleer layers. Rats. 1 1zebr.
predl.v strei. ne.123:13-17 '55. (MIRA 9:7)

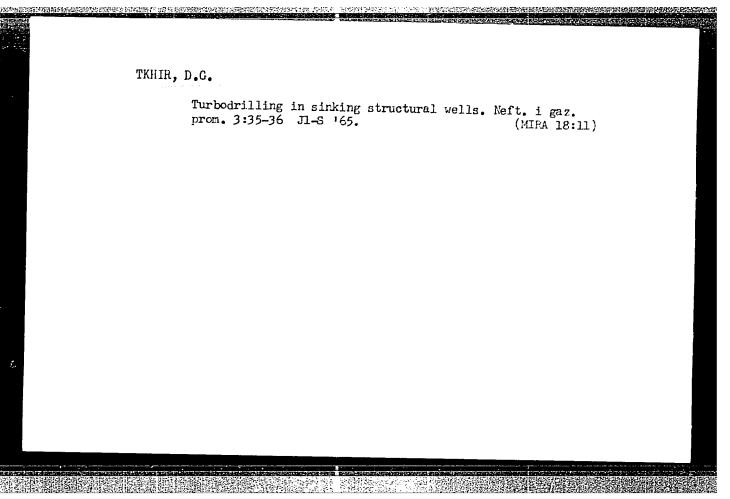
(Parquetry)

VASADZE, Te.M., AKHINYALKII, G.Kh.

Turbodrilling of mine shafts. Azerb. neft. khoz. 37 no.8:
21-24 Ag '58. (MIRA 11:11)

(Shaft sinking)





Grigor'yeva, A.	movskiy, O.A.; Andreyeva I.; Ivanets, N.I.; Ivany kachenko, Zh. Ya.; Tkhir	uta, M.M.: Kozi	rskiy, LiYe. G ar, L.T.; Rayki	oncharova, T.A.; ner, L.D.;
TITLE: Determi	nation of the developmenting for oil and gas in	t level of the	technique and	technology of geo-
SOURCE: Ref. :	h. Geofizika, Abs. 1D97		•	<i>1</i> %
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TOPIC TAGS: preserved to the clear of the electro-	ospecting, seismic prospegnetometer,  ogical-geophysical prosped 1962 was analyzed. At produced by prospecting survey to s/km². The output and precent survey is basically r km² in 1960 and 47.2 reconnected, and its motthe Ukraine, Volume of se	gravimetry ecting for oil esent all the o with the M-2 ms ecision of the y complete. The oubles in 1962, anomalies, Insp bility, it has	and gas, complete and gas, complete aromagnetic account of the Highly precise ite of the relation been afformation	leted on the Ukrai- critory of the Uk- ne cost of study survey is much bet- total survey was be gravimeters lative cheapness of coded the deserved

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TKHOMIROV, D.F.

Staff catchers must be improved. Avtom., telem. i sviaz'2 no.1:
39 Ja '58.

(MIRA 11:1)

1. Starshiy elektromekhanik Volkhovstroyevskoy distantsii signalisatsii i svyazi Kirovskoy dorogi.

(Railroads--Signaling)

ADAMOVICH, A.V., kand.tekhn.nauk; TKHOMIROV, Ya.V., kand.tekhn.nauk

Statistical investigation of the strength of the block carter of a V-engine. Avt.prom. 27 no.8:8-11 Ag '61. (MIRA 14:10)

l. Nauchno-issledovatel'skiy avtomobil'nyy i avtomotornyy institut.

(Automobiles-Engines)

LEVIN, V.I.; GOLUTVINA, M.M.; TKHOMIROVA, Ye.A.

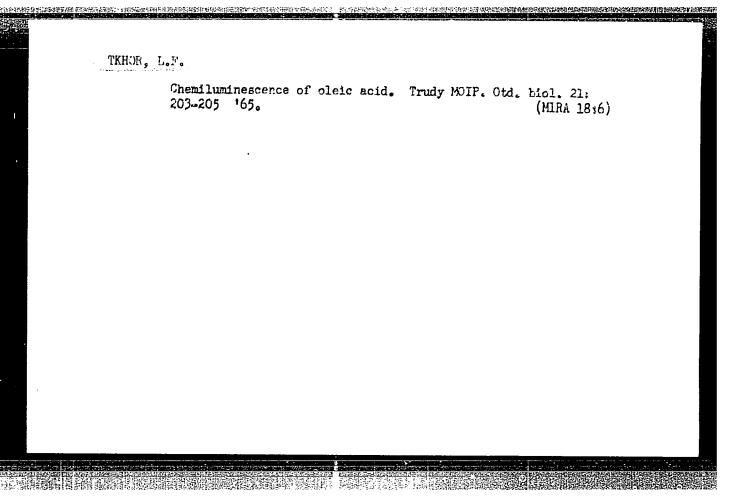
Preparation of arsenic-74 from neutron-irradiated selenium.
Radiokhimiia 3 no.5:597-600 '61. (MIRA 14:10)

(Arsenic--Isotopes) (Selenium) (Neutrons)

BASARGIN, V.A., inzh.; GRINBERG, V.L., inzh.; TKHOR, A.P., inzh.; ZAZIMKO, V.N., inzh.

Mechanization of duck breeding farms. Mashinostroenie no.5: 83-84 S-0 164 (MIRA 18:2)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"



TKHOR, L.F.; KOZLOV, Yu.P.

Effect of some antibiotics on the chemiluminescence of cleic acid. Biofizika 10 no.3:523-524 165. (MIRA 18:11)

1. Biologo-pochvennyy fakulitet Moskovskogo gosudarstvennogo universiteta imeni Lomonosova. Submitted July 11, 1964.

TKHOR, T.G.; PANKRATOV, M.A., prof., nauchnyy rukovoditel' raboty

Restoration of reflexes from the auricular skin of a rabbit as related to the regeneration of nerves. Uch. 2ap. Ped. Inst. Gerts. 239:131-137 '64. (MHA 18:3)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

DEDNYY, M.S.; TKHOR, V.G. (Dnepropetrovsk)

Oldest hospital in the Ukraine. Sov. zdrav. 21 no.2:60-63
'62. (MIRA 15:3)

(UKRAINE--HOSPITALS)

USSR/Farm Animals. Sheep and Goats.

Q

Abs Jour: Ref Zhur-Biol., No 17, 1958, 78766.

Author : Lermontov, V. S., Tkhor, Ye. S.

Inst

Title : On the Effectiveness of Winter Lambing of

Sheep.

Orig Pub: Ovtsevodstvo, 1958, No 1, 5-6.

Abstract: In a test group (February birth), 5% of the

ewes were barren, 0.5% of the lambs died; 124 lambs of 100 ewes were raised. In the control group (April birth) respectively: 15, 2.1 and 100. Difference in live weight of the lambs for 5 months in favor of the test group comprised: with young rams 2.7 kg, ewe yearlings

Card : 1/2

USSR/Farm Animals. Sheep and Goats.

Q

Abs Jour: Ref Zhur-Biol., No 17, 1958, 78766.

0.6 kg; in length of wool, respectively: 0.7 and 0.6 cm.

Card : 2/2

44

L 13064-63

BDS

ACCESSION NR: AT3003010

5/2927/62/000/000/0235/0235

AUTHOR: Miselyuk, Ye. G.; Tomashevskaya, R. L.; Tkhorik, Yu. A.

TITLE: Ten-element diode matrix (A brief information) [Report of the All-Union Conference on Semiconductor Devices held in Tashkent from 2 to 7 October 1961]

SOURCE: Elektronno-dy\*rochny\*ye perekhody\* v poluprovodnikakh. Tashkent, Izd-vo AN UzSSR, 1962, 235

TOPIC TAGS: semiconductor matrix, diode matrix, ten-element matrix

ABSTRACT: Soviet-manufactured IM-10 ten-element diode matrices are intended for passive-storage computers. The IM-10 matrix comprises 10 diodes with a common base mounted on a 10 x 10 sq mm panel; it has the following parameters (with 20% spread): maximum forward current 0.25 amp, maximum peak current 1 amp, forward resistance at 0.6 v 2-4 ohms, peak resistance 5 ohms, maximum reverse current 6 microamp, breakdown voltage 60-80v, operating temperature range -50 +65C. Orig. art. has:

ASSOCIATION: Akademiya nauk SSSR (Academy of Sciences SSSR); Akademiya nauk Uzbekskoy SSR (Academy of Sciences UzSSR); Tashkentskiy gosudarstvenny\*y (Tashkent St. Un.)

•	ASD/ESD-3 Pz-4/Pm-4 JD/IJP(C) ACCESSION NR: AT3003011	S/2927/62/000/000/0236/0243
	AUTHOR: Miselyuk, Ye. G.; Tomashevskaya, R	•
	TITLE: Germanium diffusion diodes for puls Conference on Semiconductor Divices, Tashk	a cibruita [Parant et the All III.
	SOURCE: Elektronno-dy*rochny*ye perekhody* AN UzSSR, 1962, 236-243	v poluprovodnikakh. Tashkent, Izd-vo
	TOPIC TAGS: germanium diode, IDG-1 diode	
	ABSTRACT: As a prerequisite to the develor transients in Ge diffusion diodes were stutime of materials, geometric factors, and penaracteristics of diodes were investigated level (or forward current) and reverse voltime, for various lifetimes and base thickness new Ge diode, IDG-1, with these parameter 0.5-microsec pulse and 1/2000 pulse duty for 1 amp, 0.6 - 0.8 v; forward resistance, 0.5	died. Effects of resistivity and lifen junction processing on the switching d. Particularly, the effect of injection tage on the reverse-resistance recovery esses, were investigated. As a result, rs was developed: peak current with a actor, up to 15 amp; voltage drop at

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ACCESSION NR: AT3003011

microamp; breakdown voltage, 80-100 v; recovery time, 0.25 microsec or less; pulse forward resistance, 5 ohms; working temperature range, -100 +65C. The IDG-1 diode was tested in various computers and is recommanded for use in switching circuits, ferrite-diode circuits, ferroelectric circuits, discriminators, registers, and other circuits involving heavy currents. The diode was set in small-lot production. Orig. art. has: 7 figures, 5 formulas, and 3 tables.

ASSOCIATION: none

SUBMITTED: 00 DATE ACQ: 15May63 ENCL: 00

SUB CODE: PH, GE NO REF SOV: 006 OTHER: 008

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

-2/2

247700

37873 s/185/62/007/005/003/013 D407/D301

AUTHOR:

Tkhoryk, Yu.O.

DENTE DESCRIPTION DE LA CARLOS DEL CARLOS DE LA CARLOS DEL CARLOS DE LA CARLOS DE L

TITLE:

Emissivity of diffused p-n junctions

PERIODICAL:

Ukrayins'kyy fizychnyy zhurnal, v. 7, no. 5, 1962,

476 - 481

TEXT: The distribution of carrier concentration in a diffused p-n junction is considered which has been obtained by the method of thermodiffusion. A formula for the emissivity of p-n junctions is obtained. It was shown by K.B. Tolpygo (Ref. 1: ZhTF, 27, 884, 1957) obtained. It was shown by K.B. Tolpygo (Ref. 1: ZhTF, 27, 884, 1957) that the coefficient of injection  $\gamma$  is not a constant of the p-n that the coefficient of injection  $\gamma$  is not a constant of the p-n junction (as in Shockley's theory), but depends on the structure of junction, the properties of the contact metal-semiconductor and the junction, the properties of the contact metal-semiconductor and the magnitude of the current. The parameter  $\beta$ , called by Tolpygo the emissivity of the p-n junction, combines all these properties. In Ref. 1 (Op. cit.) the parameter  $\beta$  was calculated for linear and exponential distributions of the doping impurities and criteria for exponential distributions of the doping impurities and criteria for high emissivity (i.e. large values of  $\beta$ ) were derived. Large values of  $\beta$  are particularly important for pulse diodes, where a low direct card 1/3

S/185/62/007/005/003/013 D407/D301

Emissivity of diffused p-n junctions

resistance is required; as pulse diodes are normally obtained by the diffusion method, it is important to derive analogous criteria for diffused p-n junctions. It is assumed that the p-n junction is for diffused p-n junctions. It is assumed that the p-n junction is formed by the diffusion of donors in a p-type semiconductor. Thereformed by the donor concentration decreases with the distance from the edby the donor concentration decreases with the distance from the edby the donor concentration of the donors, and t - the time of diffuthe diffusion coefficient of the donors, and t - the time of diffusive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing. The n-layer is divided into 3 regions; the points sive annealing.

$$\beta = \frac{N(0)/Q_{+}}{1 + A\ddot{s}_{0} \frac{N(0)}{Q_{+}}},$$
(15)

where  $Q_+$  is the transmittance (for holes) of the contact;  $N=n/p_p$  (n being the electron concentration and  $p_p$  - the equilibrium concentration 2/3

Emissivity of diffused p-n junctions . S/185/62/007/005/003/013

tration of holes in the base),  $A = e \cdot \frac{\rho_0}{4\pi\tau}$ . The accuracy of the above approximation is estimated. Thereby one obtains

Formulas (15) and (24) are in agreement with the corresponding formulas of Ref. 1 (Op.cit.). It is noted that the emissivity of the p-n junction (in the case of a linear impurity distribution) increases with dv/dg (v being related to the donor-concentration distribution); for a diffused p-n junction dv/dg is a variable quantity. It is also noted that, other conditions being similar, the emissivity of diffused p-n junctions is higher than with a linear impurity-distribution. There are 1 figure and 5 references: 3 Soviet-bloc and 2 non-Soviet-bloc. The most important English-language publication reads as follows: J.R.A. Beale, Proc. Phys. Soc., 70, 1087, 1957.

ASSOCIATION: Instytut napivprovidnykiv AN URSR (Institute of Semi-

submitted: conductors of the AS UkrRSR) Kyyiv
January 24, 1962

Card 3/3

P.C.H.

S/109/62/007/006/021/024 D234/D308

9,4340 AUTHORS:

Kolomiyets, B. T., Litvinova, E. M., Miselyuk, Ye. G.,

Tkhorik, Yu. A. and Shilo, V. P.

TITLE:

Effect of fusible glass coating on the characteristics

of germanium diodes

PERIODICAL:

Radiotekhnika i elektronika, v. 7, no. 6, 1962,

1054-1055

Three types of glass coatings on germanium diffusion diodes TEXT: were tested: As2Se3.I1.5; As2Se3.TI2Se; ZAs2S3.T12S. The whole exposed surface of the semiconductor, including the p-n transition, was coated. A graph of a typical variation of V-A characteristics after coating is given. The characteristics so obtained were practically unchanged over many days. Glass coating is found to improve essentially the inverse branches of the characteristics. The effect of all three types of glass is nearly the same. Improvement of characteristics was also observed when the glass had been re-

Card 1/2

Effect of fusible ...

S/109/62/007/006/021/024 D234/D308

moved immediately after coating which disagrees with the result of other Soviet authors. There is 1 figure.

ASSOCIATION:

Institut poluprovodnikov AN USSR; Fiziko-tekhnicheskiy institut im. A. F. Joffe AN SSSR (Institute of Semiconductors, AS UkrSSR; Physico-Technical Institute im. A. F. Joffe, AS USSR)

SUBMITTED:

February 13, 1961

Card 2/2

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

TKHORIK, Yu.A. [Tkhoryk, IU.O.]

Accumulation of minority current carriers in semiconductor diodes with a narrow base. Ukr. fiz. zhur. 8 no.10:1128-1141 0 '63. (MIRA 17:7)

1. Institut poluprovodnikov AN UkrSSR, Kiyev.

TKHORAK YA-#-

ACCESSION NR: AP4017393

8/0185/64/009/002/0139/0149

AUTHOR: II'yenkov, A.I.; Tkhory\*k, Yu. O.

TITLE: Measurement of short lifetimes of current carriers in semiconductor devices by the pulse method

SOURCE: Ukrayins'ky\*y fizy\*chny\*y zhurnal, v. 9, no. 2, 1964, 139-149

TOPIC TAGS: semiconductor, semiconductor lifetime, pulse method, current carrier effective lifetime, diode, transistor

ABSTRACT: The effective lifetime  $\gamma_e$  of the minority carriers in the base region of a semiconductor device is the most important parameter which determines the frequency  $\gamma_e$  in diodes have been proposed but the most practical and direct method is based on the investigation of the transient process which arises during diode switching. For values of diode is switched from forward to reverse, the reverse current is established in two stages the or phase of constant reverse current (when the diode resistance is small compared to the external circuit resistance) and the phase of current decay (which begins when rent pulse length ti, its magnitude If, as well as the magnitude of the reverse current

(1) ·

ACCESSION NR: AP4017393

Ir which flows during  $t_{lim}$ , are related to  $\gamma_e$  by the formula:

$$\operatorname{erf} \sqrt{\frac{t_{\lim}}{\gamma_e}} = \frac{1}{B_0 + 1} \operatorname{erf} \sqrt{\frac{t_1 + t_{\lim}}{\gamma_e}}$$

where  $B_0 = I_V \text{ and } B_0 \geqslant 0.5$ .

Equation (1) is valid when the base region is much longer than the diffusion length of the minority carriers and when the switching pulse has zero rise time. When the finite rise time in the leading edge of the switching pulse is taken into account the use of equation (1) may lead to serious errors. For a planar p-n junction diode switched by a trapezoidal pulse, when the forward and reverse resistances in the external circuit may be unequal (Fig. 1 of the Enclosure), the following formula is derived, which gives the desired minority lifetime  $\gamma$  in terms of measurable parameters:

Card 2/194

ACCESSION NR: AP4017393

$$1 = \frac{2(a+b+c)-1}{2a} \operatorname{erf} \sqrt{a+b+c} + \frac{\sqrt{a+b+c}}{a\sqrt{\pi}} e^{-(a+b+c)} + \int + \frac{aB_0-b}{b} \left[ \frac{2(b+c)-1}{2a} \operatorname{erf} \sqrt{b+c} + \frac{\sqrt{b+c}}{a\sqrt{\pi}} e^{-(b+c)} \right] - \frac{B_0}{b} \left( \frac{2c-1}{2} \operatorname{erf} \sqrt{c} + \frac{\sqrt{c}}{\sqrt{\pi}} e^{-c} \right).$$
 (2)

where a =  $\overrightarrow{P}$ ,  $b = \overrightarrow{P}$ , and the intervals  $t_f$ ,  $t_p$  and  $t_r$  are defined in Fig. 2 of the Enclosure. Equation (2) can be simplified considerably if the constant reverse current interval, tlim, is shorter than the duration of the leading edge of the switching pulse (Fig. 2b). A general Laplace transform equation from which an expression analogous to Eq. (2) can be derived for any switching pulse shape, is also derived. The errors which can be encountered in calculation, when the finite duration of the leading edge of the trapezoidal pulse is neglected (as in Eq. 2), are summarized in Fig. 3 of the Enclosure. Some experimental data which support the conclusions reached in this paper are tabulated in the original. It is evident that for large  $B_0$  values the values of  $\gamma_1$  are too low. The

ACCESSION NR: AP4017393  $\gamma_{e-\gamma_1}$  is systematic and ranges from 13.6-21.6% for  $B_0=0.2$ , from 7.2 to error 17.7% for  $B_0 = 0.459$  and from 22.2 to 42.4% for  $B_0 = 1$ . The accuracy in the estimate of  $\gamma_0$  is 6.6% and also  $\gamma_2 < \gamma_0$  even though the error in  $\gamma_2$  is smaller than in  $\gamma_1$ . "The authors thank E. M. Ly\*tvy\*noviy for construction of the diodes." Orig. art. has: 3 ASSOCIATION: Insty\*tut avtomaty\*ky\* ta elektrometriyi, SV AN SSSr, Novosibirsk (Institute of Automation and Electric Measurement); Insty\*tut napivprovidny\*kiv AN SUBMITTED: 05Aug63

DATE ACQ: 19Mar64

ENCL: 03

SUB CODE: PH

NO REF SOV: 014

OTHER: 004

Card

ACCESSION NA: AP4038648 S:0109.64/909/005/0876/0881

A' 'HOR Bondarenko, V. N., Litvinova, E. M., Snitko O. V., Tkhorik, Yu. A.

LE. Effect of some coatings and thermal treatment of the surface

SOURCE: Radiotekhnika i elektronika, v. 9, no. 5, 1964, 876-881

TOPIC TAGS: silicon, metal coated silicon, germanium, metal coated & germanium, surface recombination, surface recombination rate

ABSTRACT: An experimental investigation of the effects of (i) low-temperature annealing of Si and Ge in He atmosphere and in contact with low-melt inorganic glasses and (2) coating Si and Ge with a very thin film of Au or Al upon the surface recombination rate (s) is reported Single-crystal, 0.4-0.7-mm thick. Si and Ge plates were tested Four types of glass were used: (1) Tlyse As Sewith a softening temperature of 109C) AsySey + 1.5 (85C), AsySey + 1.7 (70C).

Card 1/2

L 20501-65

ACCESSION MR: AP4038648

and  $\text{Tl}_2 S \cdot 2 \text{As}_2 S_3$ . It is found that annealing of n- or p-type Ge results in an therease of a by 2-3 times, a subsequent contact with glass results in an overall increase of a by 3-6 times. Annealing of Si results in 2-4 times lower a, with a subsequent glass treatment, a was reduced to about 300 cm; sec. The same value of s was obtained by a vacuum-spraying of n-Si by gold (0.1-0.2 micron thick). The preliminary results of Al spraying were negative. "The authors wish to thank B. T. Kolomiyets and Y. P. Shilo for lending the glasses." Orig. art. has: 1 figure, 2 formulas, and 3 tables.

ASSOCIATION: Institut poluprovodnikov AN UkrSSR (Institute of Semiconductors,

AN UKTSSA)

SUBMITTED: 22Mar63

ENCL: 00

SUB CODE: MM, SS

NO REF SOV: 006

OTHER: 004

Cara 2/2

TKHOR VK 410

L 14799-65 AFWL/ASD(a)-5/ESD(t) ACCESSION NR: AP4044168

\$/0195/64/309/00%/0851/0861

AUTHOR: Gry\*bny\*kov, Z. S., Gribnikov, Z. S., Tkhor\*\*k, Yu O

تتع

TITLE: Transient processes of storage and dissipation of nonequilibrium carriers in semiconductor diodes. II High injection levels

SOURCE: Ukrayins'ky\*y fizy\*chny\*y zhurnal, v. 9, no. 8, 1964, 851-561

TOPIC TAGS: transient process, semiconductor, carrier storage, carrier dissipation, semiconductor diode

ABSTRACT: The processes of storage and dissipation of non-equilibrium charge carriers in a  $p^+$ -i-n $^+$  diode at high injection levels are investigated, and expressions are derived for the transient concentrations and for the dissipation time. The latter are valid for both high and low currents. The conclusion that the glode characteristics has a minimum has been experimentally verified. The comparison of the volt-ampere characteristics of the diodes of the  $p^+$ -i-n $^+$  and  $p^+$ -i-metal types shows that the transient processes in the first type are determined by the

Card 1/2

L 14799-65

ACCESSION NR: AP4044168

diffusion, and in the second type by the drift. The author is grateful to A. P. Klimenko for help with the experiment. Orig. art. has: 8 figures, 32 equations

ASSOCIATION: Institut poluprovodnikov AN URSR (Institute of Semiconductors AN URSR)

SUBMITTED: 19Jan64

ENCL: 00

SUB CODE:

SS

NO REF SOV: 012

OTHER: 003

Card 2/2

GRIENIKOV, Z.S. [Hrybnykov, Z.S.]; TKHORIK, Yu.A. [Tkhoryk, IU.O.]

Transients of storage and decay of nonequilibrium carriers in semiconductor diodes. Part 3. Symmetric thin diodes at superhigh injection levels. Ukr. fiz. zhur. 9 no.9:943-947 S \*164. (MIRA 17:11)

1. Institut poluprovodnikov AN UkrSSP, Kiyev.

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

GORBAN', A.P.; TKHORIK, Yu.A.

Device for measuring the caracitance of semiconductor discuss. Avtom. i prib. no.2:57-60 Åp-Je 163. (MTRA 18:8)

1. Institut poluprovodníkov Ali Skrock.

F.A.; IL'YENKOV, A.T.; TKHOBIK, Yu.A.  Evaluation of the pulse characteristics of summorphists; Sindes.		
Trudy Inst. avtom. i elektrometr. 30 AN SOSR no.10.68485 165. (MISA 18:8)		

TKHORIK, Yu.A.

Effect of the dependence of the recombination speed in the plane of a non rectifying contact from the injection level on the spread-

ing time. Radiotekh. i elektron. 10 no.3:574-576 Mr 165.
(MIRA 18:3)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

TKHORIK, Yu.A.

Nature of inertial p-n junction diodes with small leakage rates of the minority current carriers through a nonrectifying junction. Radiotekh. i elektron. 10 no.6:1162-1163 Je 165.

(MIRA 18:6)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

KLIMENKO, A.P. [Klymenko, A.P.; TKHORIK, Yu.A. [Tkhoryk, IU.O.]

Use of the simultaneous diffusion of two admixtures in manu-

facturing quick-response diodes. Ukr. fiz. zhur. 10 no.2:238-239 F '65. (MIRA 18:4)

1. Institut poluprovodnikov AN UkrSSR, Kiyev.

KLIMENKO, A.P. [Klymenko, A.P.]; TKHORIK, Yu.A. [Tkhoryk, IU.O.]

Effect of the duration of the pulse front on direct transients in semiconductor diodes. Ukr. fiz. zhur. 9 no.11:1271-1273 N '64 (MIRA 18:1)

1. Institut poluprovednikov AN UkrSSR, Kiyev.

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

GRIBNIKOV, Z.S. [Hrybnykov, Z.S.]; TKHORIK, Yu.A. [Tkhoryk, R.C.]

Transient processes of storage and decay of nonequilibrium current carriers in semiconductor diodes. Fart 1, low injection levels. Ukr. fiz. zhur. 9 no.6:648-658 Je :64.

(MIRA 17:11)

1. Institut poluprovodnikov AN UkrSSR, Kiyev.

BONDARENKO, V.N.; LITVINOVA, E.M.; SNITKO, O.V.; TKHORIK, Yu.A.

Effect of thermal treatment and some coatings on the velocity of ~i and Ge surface recombination. Radiotekh. i elektron. 9 no. 5 876-881 My ¹64. (MIRA 17:7)

1. Institut poluprovodnikov AN UkrSSR.

ACCESSION NR. APSOUTING

5/0109/65/010/003/0574/0576

AUTHOR: Tkhorik, Yu. A.

TITLE: Effect of the recombination rate at the nonrectifying contact plane and the injection level upon the injection time.

SOURCE: Radiotekhnika i elektronika, v. 10, no. 3, 1965, 574-576

TOPIC TAGS: semiconductor characteristic, depletion time, semiconductor property

ABSTRACT: Several Soviet and Western articles are briefly reviewed in figuring out the effect of the injection level on the recombination rate in (ground-surface) p-Ge of thick-base diodes. A formula (4) for the depletion time is developed. Coating a ground Ge surface with Sn does not affect the states responsible for the recombination rate; this fact was experimentally proven with two specially designed diodes. "In conclusion, the author wishes to thank V. G. Litevchenko

Card 1/2

L 36207-65

ACCESSION NR: AP5007109

for his valuable hints, and T. M. Agakhanyan for a discussion." Orig. art. has:

3 figures and 6 formulas.

ASSOCIATION: none

SUBMITTED: 28Mar64

ENCL: 00

SUB CODE: EC

NO REF SOV: 006

OTHER: 005

Card 2/2 /0

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L 8827-65 EWT(m)/EWP(q)/EWP(b)
                               SSD/ASD(a)-5/AFWL/RAEM(c)/ESD(c)/ESD(gs)
 ESD(dp)/ESD(t)/RAEM(t)
 ACCESSION NR: AP4043094
                                         5/0185/64/009/007/0733/0743
 AUTHOR: Kly*menko, A. P. (Klimenko, A. P.); Tkhory*k, Yu. O. (Tkhorik,
 TITLE: Investigation of recombination in nickel atoms in p-germenium
SOURCE: Ukrayins'ky*y fizy*chny*y zhurnal, v. 9, no. 7, 1964, 733-
TOPIC TAGS: injection level, current carrier recombination, current
carrier lifetime, diode saturation current, germanium, nickel, nickel
impurity concentration, semiconductor, semiconductor device, semicon-
ABSTRACT: The dependence of the lifetime t of current carriers in p-
Ge diodes doped with Ni on the injection level and the temperature
has been investigated. It was found that in diodes the dependence of
on temperature is weaker than in massive specimens because of the
influence of a surface recombination whose efficiency increases with
Card 1, 2
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L 8327-65

ACCESSION NR: AP4043094

cooling. The theoretical and observed dependence of  $\tau$  on the injection level agree qualitatively. The pulse method for measuring  $\tau$  has been theoretically analyzed. The calculations show that the pulse method provides accurate values for  $\tau$ , and  $\tau_{\infty}$  at vanishing small and superhigh injection levels. To reduce the errors in the region of medium injection levels, the parameter has to be increased for the measuring circuit  $I_2/I_1$ , where  $I_1$  is the amplitude of the forward current, and  $I_2$  is the amplitude of the reverse current after switching off the diode. As an example, a calculation was made of the dependence of the injection level on the current density at the p-n junction in p-Ge with a concentration of  $3 \times 10^{15}$  cm<sup>-3</sup> of Ni at 296K, 235K, and 185K. Orig. art. has: 6 figures and 44 formulas.

ASSOCIATION: Institut poluprovodníkov AN URSR, Kiev, (Institute of Semiconductors, AN URSR)

SUBMITTED: 05Aug63

ATD PRESS: 3106

ENCL: 00

SUB CODE: EC

NO REF SOV: 016

OTHER: 010

Card 2/2

Study of recombinations on nickel atoms in p-germanium at high injection levels. Ukr. riz. zhur. 9 no.7:733-743 Jl 164.
1. Institut poluprovodnikov AN UkrSSR, Kiyev. (MIKA 17:10)

TKHORIK, Yuriy Aleksandrovich [Tkhoryk, IU.O.]; KISINA, I.V., red.izd-va;
RAKHLINA, W.P., tekhn.red.

[Semiconductors and electric power] Napivprovidnykova energetyka.
Kyiv, Vyd-vo Akad.nauk URSR, 1959. 51 p. (MIRA 13:9)
(Semiconductors) (Photoelectric cells)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

2X.		
	L 20950-66 EWT(1) IJP(c) AT ACC NR: AP6006750 SOURCE CODE, VID (12.0) (66.4)	
	ACC NR: AP6006759 SOURCE CODE: UR/U185/66/011/001/0040/0044	
;;;· : ; ; <del>_</del>	AUTHORS: Svyechnykov, S. V. (Svechnikov, S. V.); Tkhoryk, Yu. O. (Tkhorik, Yu. A); Pysimennyy, Yu. H. (Pisimennyy, Yu. G.)	
	ORG: Semiconductor Institute UkrSSR, Kiev (Instytut napivprovidnykiv AN URSR)	•
	TITLE: Concerning the problem of a transparent contact for II-VI type photoconductors 2/1, 442-15-15	
	SOURCE: Ukrayıns kyy fizychnyy zhurnal, v. 11, no. 1, 1966, 40-44	
	TOPIC TAGS: cadmium sulfide, cadmium compound, photoconductor, photoconductivity, single crystal, optic property, electric property, metal vapor deposition, volt ampere characteristic	
	ABSTRACT: The authors discuss the possibility of using CdO films as transparent ohmic contacts for CdS-type photoconductors. The contact properties of CdS single crystals and films with CdO films were investigated, along with the optical and electrical properties of CdO films. The films were obtained by cathode sputtering of metallic	
	Card 1/2	_
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L 20950-66

ACC NR: AP6006759

cadmium in a low vacuum under the following conditions: cathode diameter -- 6 cm, cathode-anode distance -- 1.6 -- 1.8 cm, current -- 50 to 70 mA, voltage -- 600 V, air pressure -- 0.4 to 0.65 torr. Under these conditions the polycrystalline films were deposited at a rate of 500 -- 600 Å/min. The resistivity of CdO films measured by the four-probe method amounted to (3.2 -- 6.4) x 10<sup>-3</sup> ohm-cm, which does not contradict the data in the literature, and was temperature independent between -100 and 70C. The spectral dependence of the transmission coefficient was obtained. The volt-ampere characteristics of CdS films with CdO contacts were obtained at various temperature and illuminations. An investigation of the distribution of the potential along the CdS film with CdO contacts showed that the gradient of the potential decreases near the contacts. These results and also data on the noise characteristics of the contacts indicate that they are ohmic. Orig. art. has: 4 figures and 1 table.

SUB CODE: 20/ SUBM DATE: 05Mar65/ ORIG REF: 003/ OTH REF: 004

Card 2/2 M95

ACCESSION NR: AP4040934

S/0185/64/009/006/0648/0658

AUTHOR: Gry\*bny\*kov, Z. S. (Gribnikov, Z. S.), Tkhory\*k, Yu. O. (Tkhorik, Yu. A.

TITIE: Transient processes of storage and decay of nonequilibrium carriers in semiconductor diodes

SOURCE: Ukrayins'ky\*y fizy\*chny\*y zhurnal, v. 9, no. 6, 1964, 648-658

TOPIC TAGS: Semiconductor diode, nonequilibrium carrier, transient decay, transient diode decay, transient diode storage, p-n junction, diode performance

ABSTRACT: Transient processes are considered in semiconductor diodes when the current through the diode is given (forward bias on the p-n junction). It is shown that when the width of the base is small, the time dependence of the minority carrier density is described by a simple exponential function; for this function the time constant is calculated with various recombination velocities on the unrectifying contacts and emitter efficiencies. Time dependences of this density were also obtained with different base widths. The recovery time vs if was calculated to the contacts and emitter efficiencies.

lated for different base widths, emitter efficiencies and recombination velocities. Orig. art. has 21 numbered equations, 5 graphs and an appendix.

Card 1/2

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. !	ACCESSION NR: AP4040934		ł
	ASSOCIATION: Insty*tut napivprovidny*kiv AN UkrSSR Kiev (Institute i Semiconductors, AN UkrSSR)	for	
· •	SUBMITTED: 09Jan64	ENCL: 00	
! !	SUB CODE: EC NO REF SOV: OO4	OTHER: 004	•
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KOTENKO, A.D.; TKHORIVSKIY, A.M.

First-year students of a pedagogical institute study techniques of measurement. Politekh. obuch. no.8:67-68 Ag '59.

(MIRA 12:10)

1. Pedagogicheskiy institut, g. Vinnitsa. (Measuring instruments)

TO A CONTROL TO THE POST OF TH

GLADYSH, Vladimir Vikent'yevich, inzh.; GLIK, Arnol'd Konstantinovich, inzh.; SAKHAROV, Grigoriy Grigor'yevich, inzh.; TKHORZHEVSKIY, Dmitriy Aleksandrovich, inzh.; MAKOVSKIY, G.M., inzh., red.; OSIPOVA, L.A., red. izd-va; CHERNOVA, Z.I., tekhn. red.

[Technology of the production of rolling mill equipment] Tekhnologiia proizvodstva prokatnogo oborudovaniia. By V.V.Gladysh i dr. Moskva, Gos. nauchno-tekhn. izd-vo mashinostroit. lit-ry, 1960. 288 p. (MIRA 14:9)

(Rolling mills) (Machinery industry)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001755930004-7"

D'OMIN, A.I., nauchnyy sotr.; PTLIPENKO, Yu.P.[Pylypenko, IU.P.],
prepodavatel' sredney sholy; TKHORZHEVSKIY, D.O.
[Tkhorzhevs'kyi, D.O.], red.; SHEVCHENKO, L.I., tekhn.red.

[Classes in fitting and repairing; tractor repair]Uroki z
sliusarno-remontnoi spravy; remont traktora. Za red. K.I.
Shvetsova. Kyiv, Radians'ka shkola, 1962. 74 p.

(MIRA 16:3)

1. Nauchno-issledovatel'skiy institut peagogiki Ukr.SSR (for
D'omin).

(Tractors--Maintenance and repair)

solved by	olem related to the method the application of low-fr .28:84-89 \$56. (Frequency measurements	ednesich no ilitoria.	(MIRA 10:12)

CTRSPL Vol. 5 No. 1 Jan. 1952

15 horzhowskii, C.A. and Shembel', B.K.

The symbolization of a tube oscillator by a harmonic of the fundamental frequency zburnal Technicheskoi Fizibi 17, 215-10 (1947)

TRANSLATI: 1.5 FUFILEBLE AT BROCKHAVEN NATIONAL LAPORATORY